

**Defect-oriented test generation using probabilistic estimation**

Cibakova, Tatiana; Fischerova, Maria; Gramatova, Elena; Kuzmicz, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes**  
Proceedings of the 8th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2001 : Zakopane,  
Poland, 21-23 June 2001 / p. 131-136 : ill

**Delay fault investigation at the register transfer level**

Fischerova, Maria; Gramatova, Elena BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia :  
proceedings 1996 / p. 141-144

**Hierarchical test generation for combinational circuits with real defects coverage**

Cibakova, Tatiana; Fischerova, Maria; Gramatova, Elena; Kuzmicz, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes**  
Microelectronics reliability 2002 / p. 1141-1149 : ill